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March 3, 2006

**FACSIMILE TRANSMISSION COVER SHEET**

To: Examiner T. SHIH  
Group Art Unit 3735  
U.S. Patent and Trademark Office

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Number of Pages Sent (Including cover sheet): 2

Prepared By: sms

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**Draft Amended Claims:**

1.(Amended) An optometric apparatus for subjectively examining visual functions of an eye of an examinee, the apparatus including:

a disposing unit for disposing an optical element in front of the examinee's eye;

a cornea position alignment optical system for checking a vertex distance between a back surface of the disposed optical element and a corneal vertex of the examinee's eye;

wherein the alignment optical system includes an aligning scale plate provided with a scale for checking the vertex distance, a reticle plate provided with a reticle and placed in a different place from the aligning scale plate, and a first reference mark and a second reference mark for positioning an eye of an examiner in a point at a predetermined distance from the reticle plate,  
the first reference mark is provided to have a first positional relation with respect to the aligning scale plate and the reticle plate,

the second reference mark is provided to have a second positional relation with respect to the aligning scale plate and the reticle plate, different from the first positional relation,

the first and second reference marks [being provided in different places and] appearing, to the examiner's eye, to have a predetermined positional relation with each other when the examiner's eye is positioned in the point at the predetermined distance from the reticle plate and views the reference marks from that point.

4.(Amended) The optometric apparatus according to claim 1, wherein shapes and positions of the first and second reference marks are determined so that the reference marks appear overlapped, to the examiner's eye, when the examiner's eye is positioned in the point at the predetermined distance from the reticle plate and views the reference marks from that point.

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